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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/625,614	CHANG ET AL.	
Examiner	Art Unit	
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Class	Subclass	Date	Examiner
UPDATED	&	1/16/2007	DV
375	265	1/16/2007	DV

TNI	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
375	233, 265	1/16/2007	DV
375	350	1/16/2007	DV

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